## **Supplementary Information**

## Nanostructure-induced $L1_0$ -ordering of twinned single-crystals in CoPt ferromagnetic nanowires

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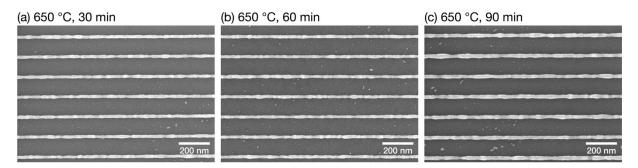
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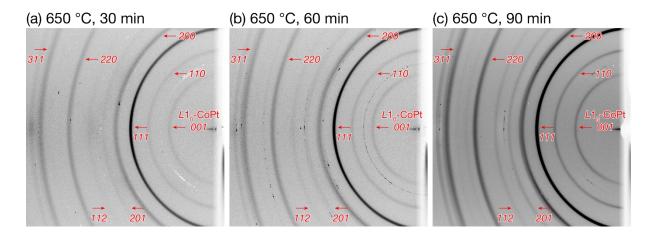
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**Fig. S1.** Typical top-view scanning electron microscope (SEM) images of [Co (3.6 nm)/Pt (4.8 nm)]<sub>6</sub> multilayer nanowires on Si/SiO<sub>2</sub> substrates after annealing at 650 °C for (a) 30 min, (b) 60 min, and (c) 90 min. Part (c) is shown again for easy comparison.



**Fig. S2.** Two-dimensional (2D) grazing incidence X-ray diffraction (GI-XRD) patterns of  $(Co/Pt)_6$  nanowires on Si/SiO<sub>2</sub> substrates after annealing at 650 °C for (a) 30 min, (b) 60 min, and (c) 90 min. The diffraction peaks of  $L1_0$ -CoPt (001, 110, 111, 200, 201, 112, 220, and 311) are indicated by red arrows. Part (c) is shown again for easy comparison.